www.SeCosGmbH.com

Headquarter Address:
8F.No.33, Lane 155, Sec.3, Bei-Shen Rd.,
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Product/Process Change Notification

PCN#	Effective Date	Issue Date
2015-10-21C-09	2016/4/21	2015/10/21

PCN Classification	Product Category
Major	Transistor

Subject
Change the assembly house.

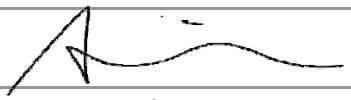
Affected Product(s)
BCP772

Description of Change(s)
The original assembly house, GTM Corporation, was shut down; thus, we change to the second assembly house.

Content of Change(s)
Assembly house.

Impact(s)
None

Attachment(s)
Reliability Test Report.

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu
Customer Approval		
Customer's Comment		
Customer's Consent with Signature		

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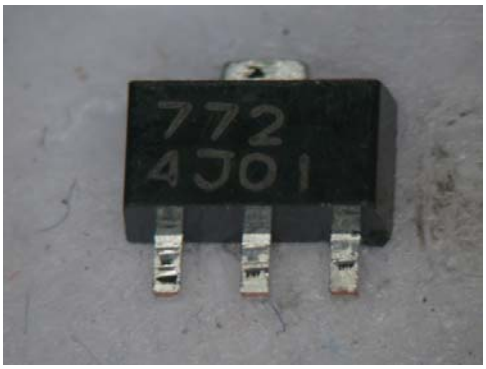
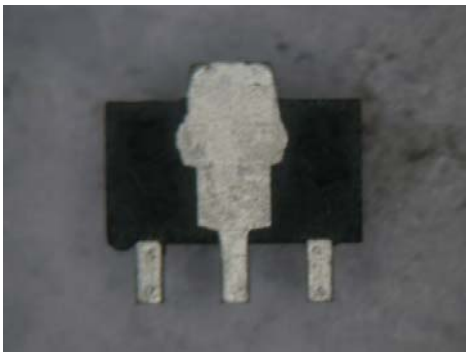
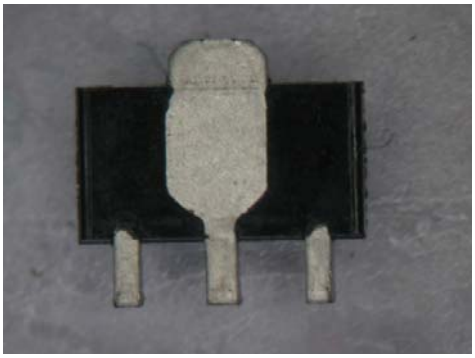
Exterior comparison Chart	
Original	New
	
Top View	Top View
	
Back View	Back View

SeCoS Corporation

Reliability Testing Summary Report

Date: 2015/10/08 Document No.: SI15 -10-105

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	BCP772	150 ± 5℃, 80%VR, T = 1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	BCP772	150℃, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	BCP772	121℃, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	BCP772	-55℃/30min, 150℃/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	BCP772	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	BCP772	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
Solderability	BCP772	245 ± 5℃, 5Sec the inspected area of each lead must have 95% solder coverage minimum		10	0	0	ACC

Judgment:

■ **qualified** □ **unqualified**

Testing Start Date: 2015.08.17 Testing End Date: 2015.10.08

Tester: King Huang Approval: Peter Yang

SeCoS Corporation

Electrical Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 25℃
Test Date: 2015.08.17
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
1	-50.22V	252.8	-219.9mV
2	-51.43V	251.1	-219.7mV
3	-48.08V	242.6	-227.9mV
4	-52.07V	246.4	-218.7mV
5	-48.14V	251.2	-214.2mV
6	-47.90V	247.7	-228.4mV
7	-53.68V	243.8	-238.5mV
8	-52.13V	248.1	-213.6mV
9	-47.80V	238.6	-223.2mV
10	-48.07V	238.0	-219.3mV
11	-53.53V	260.6	-245.7mV
12	-48.49V	245.2	-244.7mV
13	-47.83V	260.6	-230.2mV
14	-49.99V	260.5	-234.6mV
15	-47.67V	253.5	-247.7mV
16	-47.90V	241.9	-213.8mV
17	-50.63V	250.3	-229.3mV
18	-50.15V	241.3	-213.3mV
19	-51.54V	254.1	-241.7mV
20	-53.43V	251.2	-224.8mV
21	-49.85V	251.3	-219.4mV
22	-52.63V	236.3	-222.3mV
23	-52.45V	250.3	-231.7mV
24	-50.50V	243.5	-229.9mV
25	-52.27V	235.0	-220.2mV
26	-53.67V	242.9	-228.6mV
27	-51.49V	249.0	-229.3mV
28	-50.53V	249.6	-216.3mV
29	-53.13V	259.4	-219.3mV
30	-48.92V	240.7	-240.5mV

SeCoS Corporation

Electrical Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 25℃
Test Date: 2015.08.17
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
31	-49.80V	250.8	-214.4mV
32	-51.09V	258.4	-244.7mV
33	-53.86V	249.9	-246.7mV
34	-52.33V	236.5	-244.7mV
35	-51.86V	246.9	-237.3mV
36	-49.97V	237.2	-213.3mV
37	-53.26V	245.1	-219.5mV
38	-48.62V	255.4	-234.2mV
39	-48.38V	248.0	-247.1mV
40	-51.03V	235.9	-243.0mV
41	-53.81V	246.3	-216.4mV
42	-48.67V	238.7	-225.1mV
43	-48.45V	255.1	-227.9mV
44	-50.33V	235.9	-233.8mV
45	-53.17V	255.8	-240.3mV
46	-53.87V	242.7	-235.5mV
47	-48.52V	255.6	-245.5mV
48	-50.96V	256.0	-245.0mV
49	-47.75V	243.8	-239.7mV
50	-50.55V	237.8	-241.1mV
51	-50.67V	243.6	-228.8mV
52	-50.70V	255.9	-245.6mV
53	-49.18V	243.2	-216.4mV
54	-50.48V	245.9	-229.4mV
55	-47.44V	236.0	-233.4mV
56	-52.15V	240.2	-223.4mV
57	-47.80V	259.9	-244.8mV
58	-53.82V	245.4	-222.6mV
59	-53.10V	247.7	-222.7mV
60	-47.90V	236.7	-220.2mV

SeCoS Corporation

Electrical Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 25℃
Test Date: 2015.08.17
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
61	-53.07V	251.0	-228.2mV
62	-51.66V	247.2	-219.2mV
63	-51.70V	242.9	-223.6mV
64	-47.93V	249.2	-245.4mV
65	-49.33V	256.4	-235.4mV
66	-48.41V	254.8	-246.4mV
67	-49.92V	255.3	-228.0mV
68	-52.25V	254.6	-224.7mV
69	-49.16V	256.1	-213.2mV
70	-52.90V	258.4	-223.4mV
71	-48.28V	254.1	-244.3mV
72	-52.52V	235.6	-235.6mV
73	-49.26V	239.4	-221.3mV
74	-49.86V	234.8	-216.9mV
75	-52.47V	234.9	-228.0mV
76	-47.86V	242.9	-217.8mV
77	-52.75V	239.3	-213.0mV

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 150 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2015.08.17 ~ 2015.09.29
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
1	-51.29V	244.9	-237.3mV	-50.37V	240.8	-244.4mV
2	-51.30V	246.4	-226.8mV	-48.91V	260.3	-232.0mV
3	-47.84V	233.3	-229.4mV	-51.79V	236.5	-238.2mV
4	-49.29V	242.9	-230.2mV	-53.46V	240.9	-215.2mV
5	-51.37V	251.7	-247.8mV	-47.91V	250.1	-216.4mV
6	-50.93V	256.2	-223.5mV	-47.43V	249.7	-232.9mV
7	-50.50V	233.6	-228.6mV	-50.43V	238.3	-219.9mV
8	-48.80V	248.2	-244.6mV	-48.78V	243.3	-235.5mV
9	-47.59V	258.7	-231.0mV	-53.18V	260.7	-225.1mV
10	-52.10V	244.5	-221.6mV	-50.13V	257.1	-236.7mV
11	-49.57V	253.5	-222.4mV	-51.48V	237.0	-247.6mV
12	-52.79V	250.3	-223.5mV	-49.19V	256.7	-246.0mV
13	-49.05V	241.0	-214.0mV	-50.48V	236.4	-247.0mV
14	-53.14V	233.2	-239.1mV	-53.74V	245.7	-236.6mV
15	-49.25V	254.3	-234.6mV	-53.10V	260.5	-215.1mV
16	-49.07V	252.0	-225.2mV	-50.76V	251.5	-244.2mV
17	-48.34V	248.1	-230.6mV	-48.74V	238.0	-223.5mV
18	-49.97V	251.1	-233.6mV	-48.82V	252.0	-225.7mV
19	-51.91V	251.3	-222.3mV	-47.39V	236.2	-240.4mV
20	-50.96V	242.2	-242.8mV	-50.69V	258.8	-226.7mV
21	-52.35V	256.3	-235.2mV	-48.82V	233.4	-226.6mV
22	-51.44V	244.2	-239.4mV	-48.96V	244.7	-223.9mV
23	-50.37V	245.1	-213.9mV	-49.18V	247.2	-217.8mV
24	-48.52V	241.1	-214.1mV	-52.50V	246.1	-218.7mV
25	-51.77V	235.1	-220.3mV	-49.14V	245.4	-238.2mV
26	-50.66V	257.7	-227.3mV	-50.66V	239.0	-213.8mV
27	-52.12V	233.6	-215.8mV	-48.91V	239.4	-214.4mV
28	-48.88V	258.8	-241.3mV	-47.39V	246.2	-220.4mV
29	-50.10V	254.3	-247.3mV	-48.28V	253.7	-227.2mV

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 150 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2015.08.17 ~ 2015.09.29
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
30	-51.56V	252.2	-242.2mV	-51.13V	242.2	-221.0mV
31	-52.29V	257.6	-217.9mV	-53.33V	241.7	-226.6mV
32	-49.70V	239.5	-215.4mV	-49.85V	248.6	-231.4mV
33	-51.18V	257.8	-214.4mV	-51.49V	254.2	-220.3mV
34	-50.48V	253.8	-216.3mV	-49.24V	250.1	-232.8mV
35	-47.82V	257.6	-245.4mV	-53.63V	235.9	-232.0mV
36	-50.99V	259.4	-241.0mV	-53.13V	251.2	-245.9mV
37	-50.84V	246.7	-238.1mV	-48.86V	255.3	-228.8mV
38	-48.13V	233.4	-224.8mV	-48.58V	236.5	-228.5mV
39	-50.73V	249.9	-217.0mV	-53.75V	255.4	-241.9mV
40	-53.36V	243.9	-216.9mV	-48.74V	236.3	-242.2mV
41	-47.46V	234.3	-221.8mV	-51.04V	246.2	-226.2mV
42	-50.39V	240.5	-221.8mV	-48.19V	254.5	-248.0mV
43	-48.48V	246.4	-224.1mV	-50.48V	241.7	-240.5mV
44	-50.99V	240.5	-215.4mV	-52.05V	235.5	-238.2mV
45	-49.05V	246.8	-219.2mV	-49.49V	239.2	-217.5mV
46	-48.80V	242.1	-215.1mV	-51.02V	235.4	-234.4mV
47	-52.88V	250.7	-225.0mV	-51.50V	245.8	-219.4mV
48	-48.62V	243.9	-218.7mV	-47.47V	240.2	-232.9mV
49	-53.09V	247.0	-221.8mV	-47.77V	237.9	-226.8mV
50	-48.84V	250.6	-216.8mV	-48.33V	233.5	-230.8mV
51	-49.28V	234.2	-239.5mV	-53.50V	238.5	-234.9mV
52	-51.54V	254.0	-221.2mV	-52.37V	251.0	-224.0mV
53	-53.00V	249.0	-246.2mV	-53.91V	242.1	-220.5mV
54	-52.05V	245.3	-222.2mV	-48.73V	244.1	-216.6mV
55	-51.82V	250.9	-229.4mV	-49.35V	235.6	-233.9mV
56	-52.68V	245.6	-219.3mV	-53.78V	252.8	-239.1mV
57	-52.15V	253.9	-230.7mV	-51.63V	235.1	-213.3mV
58	-48.73V	249.2	-230.6mV	-52.00V	248.4	-220.8mV

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 150 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2015.08.17 ~ 2015.09.29
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
59	-48.14V	242.6	-226.5mV	-51.44V	257.0	-218.8mV
60	-52.11V	235.0	-248.0mV	-52.35V	242.1	-216.2mV
61	-49.87V	259.9	-247.6mV	-47.73V	242.8	-215.4mV
62	-51.99V	256.2	-227.5mV	-48.29V	246.4	-248.0mV
63	-50.99V	235.5	-223.2mV	-50.56V	234.1	-224.7mV
64	-49.11V	257.2	-219.9mV	-49.69V	251.2	-241.4mV
65	-49.22V	239.3	-241.8mV	-47.65V	248.4	-230.3mV
66	-48.79V	248.9	-215.5mV	-49.89V	256.5	-235.9mV
67	-48.61V	260.5	-233.5mV	-50.65V	260.0	-228.8mV
68	-49.98V	254.1	-239.2mV	-52.36V	250.1	-244.8mV
69	-51.34V	253.0	-241.4mV	-49.95V	234.8	-216.1mV
70	-48.63V	246.5	-217.5mV	-53.15V	247.9	-243.5mV
71	-47.97V	246.8	-242.5mV	-47.62V	237.0	-219.7mV
72	-48.75V	246.5	-219.4mV	-52.43V	246.9	-230.7mV
73	-51.79V	241.7	-246.8mV	-49.40V	251.1	-226.4mV
74	-47.40V	250.2	-234.0mV	-53.74V	255.1	-244.2mV
75	-50.43V	243.9	-228.7mV	-48.05V	249.7	-213.1mV
76	-50.31V	258.4	-222.7mV	-48.07V	248.2	-232.2mV
77	-49.86V	242.3	-224.0mV	-51.09V	254.1	-219.3mV

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 150℃, 1000Hrs
Test Date: 2015.08.17 ~ 2015.09.29
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
1	-49.06V	243.2	-231.7mV	-52.07V	245.6	-222.5mV
2	-52.68V	252.1	-224.9mV	-51.32V	258.3	-242.7mV
3	-49.85V	242.4	-247.2mV	-49.57V	240.1	-246.1mV
4	-47.51V	242.1	-227.7mV	-47.62V	234.5	-219.1mV
5	-52.75V	250.9	-233.2mV	-50.75V	249.4	-231.6mV
6	-53.64V	248.9	-218.8mV	-47.59V	246.7	-219.7mV
7	-51.69V	254.2	-216.1mV	-49.88V	257.9	-221.5mV
8	-48.20V	260.7	-245.6mV	-52.93V	233.8	-246.8mV
9	-52.71V	258.6	-235.4mV	-50.58V	250.1	-216.4mV
10	-49.01V	259.2	-228.4mV	-49.75V	244.6	-233.3mV
11	-52.94V	242.9	-212.9mV	-51.91V	243.1	-228.4mV
12	-51.34V	257.5	-230.8mV	-52.35V	246.9	-226.9mV
13	-49.65V	259.8	-247.9mV	-49.16V	256.9	-240.1mV
14	-48.58V	248.5	-217.2mV	-48.20V	250.1	-243.3mV
15	-50.94V	243.3	-241.5mV	-51.24V	245.6	-216.2mV
16	-51.40V	256.2	-225.4mV	-48.96V	251.6	-219.0mV
17	-47.66V	248.9	-222.7mV	-53.56V	240.8	-229.7mV
18	-49.11V	256.4	-217.8mV	-48.41V	255.9	-218.9mV
19	-49.25V	237.2	-241.7mV	-52.49V	236.6	-244.9mV
20	-52.63V	249.8	-232.1mV	-49.91V	243.4	-227.4mV
21	-49.84V	244.2	-238.7mV	-50.50V	256.5	-246.1mV
22	-53.21V	252.2	-227.6mV	-53.37V	252.5	-223.7mV
23	-53.70V	255.1	-239.4mV	-49.18V	243.4	-243.5mV
24	-52.62V	256.4	-231.2mV	-49.41V	253.3	-239.0mV
25	-52.42V	245.2	-214.0mV	-49.74V	237.5	-238.0mV
26	-49.50V	258.9	-227.3mV	-53.77V	238.3	-213.6mV
27	-49.70V	235.2	-218.2mV	-47.90V	255.2	-240.5mV
28	-52.38V	240.9	-215.0mV	-52.64V	247.7	-225.4mV
29	-50.08V	239.1	-222.0mV	-51.67V	238.6	-230.8mV

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 150℃, 1000Hrs
Test Date: 2015.08.17 ~ 2015.09.29
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
30	-47.41V	255.9	-213.1mV	-48.28V	256.4	-244.5mV
31	-51.30V	254.0	-236.3mV	-48.05V	253.3	-239.5mV
32	-53.57V	238.5	-224.5mV	-48.53V	254.9	-234.1mV
33	-50.71V	257.2	-216.5mV	-48.67V	233.6	-213.9mV
34	-47.39V	236.2	-244.3mV	-52.77V	252.1	-240.0mV
35	-48.41V	251.1	-233.0mV	-50.44V	235.8	-223.3mV
36	-48.37V	257.8	-237.3mV	-51.29V	241.5	-238.2mV
37	-50.03V	241.9	-219.9mV	-50.53V	256.7	-244.6mV
38	-52.79V	237.9	-239.2mV	-51.06V	241.3	-242.4mV
39	-48.83V	244.7	-221.6mV	-53.56V	246.1	-233.7mV
40	-50.18V	235.4	-238.0mV	-48.51V	256.0	-215.7mV
41	-52.53V	244.7	-234.6mV	-50.58V	239.1	-244.4mV
42	-48.30V	248.0	-236.3mV	-51.77V	252.5	-232.6mV
43	-48.31V	244.1	-225.0mV	-52.87V	257.4	-232.6mV
44	-51.02V	259.2	-217.8mV	-48.56V	253.8	-225.9mV
45	-52.75V	254.0	-228.4mV	-53.05V	251.7	-246.4mV
46	-51.63V	237.7	-218.4mV	-47.51V	250.6	-235.6mV
47	-48.44V	250.7	-226.7mV	-51.67V	237.3	-227.0mV
48	-48.00V	260.6	-227.7mV	-49.22V	256.0	-222.7mV
49	-52.94V	243.4	-226.9mV	-49.90V	237.4	-219.2mV
50	-48.87V	251.6	-238.9mV	-48.16V	237.8	-217.8mV
51	-48.50V	241.3	-233.0mV	-47.57V	236.8	-233.3mV
52	-48.47V	251.1	-240.7mV	-51.48V	247.9	-240.4mV
53	-49.28V	238.0	-223.0mV	-49.35V	248.3	-231.7mV
54	-48.40V	243.6	-221.0mV	-49.17V	236.6	-246.2mV
55	-50.81V	248.8	-221.4mV	-51.06V	252.5	-232.7mV
56	-48.50V	244.3	-230.9mV	-49.46V	260.4	-231.2mV
57	-51.50V	256.2	-232.6mV	-51.51V	254.4	-233.9mV
58	-53.85V	242.8	-226.6mV	-48.41V	257.1	-230.0mV

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 150℃, 1000Hrs
Test Date: 2015.08.17 ~ 2015.09.29
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
59	-48.72V	243.2	-219.6mV	-52.18V	242.1	-248.2mV
60	-49.88V	257.6	-217.4mV	-49.97V	252.9	-247.7mV
61	-50.68V	246.1	-220.5mV	-53.32V	252.5	-223.5mV
62	-49.13V	253.4	-216.3mV	-53.96V	260.2	-243.0mV
63	-52.97V	247.1	-235.1mV	-52.79V	242.1	-231.6mV
64	-48.85V	243.8	-245.1mV	-47.76V	254.6	-236.7mV
65	-52.87V	250.0	-241.9mV	-47.39V	239.6	-248.2mV
66	-48.70V	246.4	-247.1mV	-53.23V	237.5	-246.6mV
67	-47.80V	239.5	-229.8mV	-51.00V	258.9	-228.8mV
68	-51.84V	258.4	-216.0mV	-50.32V	250.5	-240.8mV
69	-47.85V	240.6	-230.6mV	-51.53V	252.2	-244.1mV
70	-48.81V	249.2	-232.2mV	-49.35V	256.4	-214.4mV
71	-49.12V	248.7	-214.0mV	-51.61V	246.5	-225.4mV
72	-48.29V	236.2	-216.1mV	-47.40V	253.7	-243.8mV
73	-52.13V	256.6	-214.9mV	-48.18V	237.5	-229.6mV
74	-50.30V	245.0	-238.9mV	-49.73V	255.7	-232.5mV
75	-49.37V	248.0	-231.4mV	-51.06V	239.6	-221.0mV
76	-51.93V	236.7	-226.8mV	-47.51V	258.9	-235.0mV
77	-51.42V	234.0	-213.0mV	-50.67V	250.0	-236.8mV

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Pressure Cooker Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2015.08.17 ~ 2015.08.25
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
1	-50.76V	240.4	-216.6mV	-47.96V	256.0	-247.4mV
2	-50.76V	254.2	-223.4mV	-48.94V	253.1	-240.1mV
3	-49.03V	246.2	-223.4mV	-48.17V	245.2	-230.7mV
4	-49.44V	236.1	-218.9mV	-49.52V	236.1	-235.5mV
5	-49.32V	241.3	-241.7mV	-47.65V	258.8	-241.5mV
6	-52.12V	243.4	-241.8mV	-47.33V	258.8	-218.2mV
7	-51.29V	234.2	-229.9mV	-48.54V	243.8	-222.9mV
8	-53.32V	248.7	-246.3mV	-52.17V	260.1	-236.4mV
9	-48.54V	233.6	-223.6mV	-51.44V	253.7	-230.6mV
10	-53.49V	248.8	-228.6mV	-49.64V	249.2	-246.7mV
11	-50.35V	260.7	-228.4mV	-48.11V	249.0	-235.7mV
12	-50.15V	246.1	-223.5mV	-49.96V	253.2	-234.5mV
13	-49.43V	234.0	-237.3mV	-48.61V	237.2	-240.8mV
14	-50.44V	256.7	-215.0mV	-52.32V	252.5	-219.9mV
15	-53.60V	256.4	-234.8mV	-51.43V	260.2	-214.1mV
16	-51.34V	245.6	-223.9mV	-53.64V	258.0	-238.3mV
17	-53.72V	241.1	-214.0mV	-47.89V	237.6	-219.7mV
18	-48.45V	247.2	-224.3mV	-52.18V	246.3	-233.6mV
19	-48.30V	256.1	-225.9mV	-48.01V	246.6	-230.8mV
20	-52.96V	255.6	-240.5mV	-50.82V	259.6	-241.8mV
21	-51.64V	253.6	-228.7mV	-51.39V	243.5	-230.8mV
22	-51.27V	243.2	-240.6mV	-48.58V	252.5	-232.6mV
23	-50.97V	249.7	-219.3mV	-52.04V	246.6	-240.4mV
24	-47.75V	250.3	-238.0mV	-48.15V	236.2	-218.1mV
25	-48.60V	253.9	-240.6mV	-49.11V	233.2	-223.8mV
26	-49.78V	246.0	-228.2mV	-48.55V	237.6	-233.2mV
27	-52.92V	240.1	-223.8mV	-52.80V	255.1	-242.7mV
28	-50.15V	254.3	-241.7mV	-51.34V	259.0	-236.6mV
29	-48.75V	252.4	-242.2mV	-48.76V	235.1	-241.7mV

SeCoS Corporation

Pressure Cooker Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2015.08.17 ~ 2015.08.25
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
30	-53.93V	259.0	-222.4mV	-49.20V	244.5	-214.7mV
31	-50.18V	258.4	-222.0mV	-48.14V	233.2	-221.4mV
32	-48.45V	259.2	-242.5mV	-49.30V	255.2	-230.1mV
33	-47.99V	252.0	-238.1mV	-50.42V	249.2	-245.5mV
34	-53.42V	235.5	-218.2mV	-50.40V	258.1	-227.5mV
35	-48.80V	235.0	-226.1mV	-49.56V	236.3	-221.4mV
36	-49.98V	239.5	-223.6mV	-52.75V	240.8	-241.1mV
37	-50.09V	250.3	-244.5mV	-49.23V	250.5	-220.5mV
38	-51.56V	246.7	-237.8mV	-48.60V	239.6	-216.7mV
39	-48.02V	234.3	-225.3mV	-49.16V	243.9	-237.5mV
40	-49.28V	251.7	-222.5mV	-52.89V	258.6	-226.9mV
41	-48.15V	250.3	-213.7mV	-50.89V	236.3	-228.9mV
42	-51.85V	258.3	-224.7mV	-51.49V	257.1	-243.1mV
43	-53.72V	257.7	-237.3mV	-49.56V	256.4	-228.7mV
44	-51.86V	256.4	-242.4mV	-48.08V	249.2	-223.3mV
45	-50.21V	258.3	-243.4mV	-49.79V	243.2	-220.7mV
46	-52.63V	238.7	-230.1mV	-49.33V	253.3	-247.7mV
47	-51.44V	241.4	-247.5mV	-53.07V	236.4	-223.9mV
48	-49.07V	237.1	-216.6mV	-48.33V	257.9	-233.4mV
49	-52.11V	249.4	-230.7mV	-53.92V	248.5	-214.9mV
50	-50.45V	235.8	-233.8mV	-47.97V	253.9	-237.5mV
51	-48.87V	243.3	-217.4mV	-49.12V	240.2	-239.1mV
52	-51.11V	242.5	-219.1mV	-53.37V	241.6	-247.0mV
53	-49.13V	259.7	-246.6mV	-49.50V	257.3	-248.2mV
54	-48.61V	252.0	-243.6mV	-47.68V	249.6	-232.9mV
55	-49.96V	249.0	-236.1mV	-49.47V	257.1	-247.0mV
56	-47.55V	250.5	-220.1mV	-52.99V	247.4	-248.0mV
57	-53.02V	236.9	-216.1mV	-52.33V	240.5	-216.0mV
58	-50.32V	243.8	-232.1mV	-51.00V	250.5	-228.8mV

SeCoS Corporation

Pressure Cooker Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2015.08.17 ~ 2015.08.25
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
59	-50.25V	254.3	-234.4mV	-51.05V	249.9	-219.1mV
60	-50.70V	236.1	-212.9mV	-47.72V	244.0	-234.4mV
61	-51.52V	253.9	-236.8mV	-53.26V	258.7	-217.0mV
62	-52.28V	259.7	-241.7mV	-50.28V	240.3	-236.2mV
63	-52.18V	245.7	-243.1mV	-51.07V	233.7	-244.5mV
64	-53.52V	249.5	-243.4mV	-51.86V	234.7	-222.6mV
65	-47.32V	256.4	-239.7mV	-53.00V	242.2	-215.6mV
66	-49.20V	244.5	-245.6mV	-48.98V	258.6	-246.8mV
67	-53.07V	238.1	-234.4mV	-51.23V	256.4	-234.2mV
68	-50.60V	238.4	-228.9mV	-53.73V	252.9	-221.7mV
69	-51.67V	248.0	-215.1mV	-49.24V	248.0	-232.5mV
70	-47.71V	244.7	-236.6mV	-49.73V	259.8	-236.4mV
71	-49.60V	245.4	-219.8mV	-51.09V	238.4	-247.4mV
72	-50.77V	237.8	-234.7mV	-53.87V	252.4	-240.7mV
73	-52.55V	257.7	-223.9mV	-53.56V	259.4	-240.3mV
74	-51.27V	238.6	-228.0mV	-48.95V	235.5	-220.7mV
75	-51.93V	240.3	-217.4mV	-53.18V	255.2	-245.5mV
76	-51.07V	248.1	-218.9mV	-51.41V	235.2	-225.5mV
77	-49.39V	233.8	-242.9mV	-50.79V	240.5	-238.5mV

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Temperature Cycle Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2015.08.17 ~ 2015.10.08
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
1	-52.34V	247.6	-226.7mV	-48.46V	260.6	-245.1mV
2	-51.05V	254.6	-235.6mV	-51.46V	255.8	-242.2mV
3	-49.98V	235.3	-222.0mV	-52.99V	234.2	-221.6mV
4	-47.72V	256.9	-215.8mV	-51.61V	259.9	-233.3mV
5	-48.65V	241.3	-220.6mV	-48.79V	251.2	-228.7mV
6	-51.99V	252.2	-225.1mV	-53.06V	234.0	-220.9mV
7	-53.52V	242.7	-244.6mV	-53.14V	252.8	-227.4mV
8	-52.20V	256.4	-222.9mV	-48.54V	257.1	-221.0mV
9	-51.52V	258.8	-244.4mV	-52.59V	248.1	-240.1mV
10	-47.81V	252.1	-235.5mV	-48.66V	250.8	-214.0mV
11	-52.58V	236.3	-214.7mV	-48.16V	241.4	-223.7mV
12	-49.99V	252.6	-213.3mV	-53.79V	245.4	-230.6mV
13	-51.88V	258.0	-216.0mV	-49.99V	244.4	-244.0mV
14	-50.67V	254.9	-223.7mV	-47.83V	240.6	-217.6mV
15	-50.94V	255.1	-225.6mV	-52.17V	241.0	-220.5mV
16	-53.12V	249.3	-213.3mV	-48.58V	251.7	-222.9mV
17	-51.02V	247.1	-217.1mV	-49.85V	243.1	-245.4mV
18	-49.46V	248.2	-215.3mV	-53.85V	243.5	-231.3mV
19	-49.75V	235.4	-239.6mV	-51.64V	258.2	-214.6mV
20	-50.36V	244.2	-226.4mV	-47.37V	253.7	-218.3mV
21	-52.08V	260.1	-223.6mV	-51.46V	239.6	-234.7mV
22	-53.81V	236.8	-230.0mV	-52.73V	241.4	-212.9mV
23	-52.89V	253.9	-242.2mV	-49.19V	238.4	-244.0mV
24	-50.15V	239.7	-237.2mV	-53.13V	237.2	-246.3mV
25	-49.64V	259.5	-224.7mV	-52.12V	257.3	-226.1mV
26	-53.44V	240.9	-221.4mV	-51.53V	249.3	-232.4mV
27	-49.11V	255.5	-226.6mV	-53.80V	235.1	-244.2mV
28	-53.00V	257.7	-213.1mV	-51.91V	259.8	-223.6mV
29	-50.53V	251.4	-223.2mV	-48.05V	253.7	-247.5mV

SeCoS Corporation

Temperature Cycle Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2015.08.17 ~ 2015.10.08
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
30	-53.82V	260.5	-233.8mV	-47.66V	241.3	-225.6mV
31	-49.57V	258.3	-231.8mV	-49.57V	237.8	-236.6mV
32	-50.65V	238.2	-215.1mV	-47.68V	233.3	-238.1mV
33	-50.28V	235.7	-214.4mV	-50.07V	252.5	-217.9mV
34	-48.58V	249.7	-228.4mV	-53.94V	254.4	-232.6mV
35	-52.28V	246.7	-241.8mV	-50.06V	233.4	-223.7mV
36	-50.40V	241.8	-225.4mV	-50.89V	244.8	-223.8mV
37	-51.17V	255.4	-222.5mV	-47.80V	254.3	-216.1mV
38	-52.86V	253.2	-243.6mV	-53.88V	238.5	-240.4mV
39	-49.50V	258.7	-236.1mV	-47.81V	251.9	-215.4mV
40	-49.94V	250.3	-214.1mV	-52.03V	251.1	-217.6mV
41	-47.57V	257.5	-223.5mV	-48.57V	233.7	-238.5mV
42	-48.73V	242.6	-221.6mV	-50.85V	245.4	-231.7mV
43	-51.89V	234.5	-242.5mV	-52.28V	244.2	-247.2mV
44	-48.07V	236.7	-243.2mV	-51.49V	256.4	-221.3mV
45	-50.22V	246.5	-227.0mV	-51.94V	252.8	-244.8mV
46	-49.81V	239.4	-237.5mV	-52.55V	240.9	-213.0mV
47	-52.12V	233.7	-241.9mV	-49.77V	241.9	-220.6mV
48	-53.17V	254.6	-223.4mV	-52.63V	247.4	-235.6mV
49	-48.92V	247.8	-248.1mV	-48.52V	241.0	-231.4mV
50	-53.94V	242.8	-235.0mV	-47.93V	246.4	-230.2mV
51	-48.09V	238.9	-225.7mV	-53.67V	252.7	-241.7mV
52	-47.43V	252.7	-243.2mV	-52.32V	241.6	-232.2mV
53	-49.22V	259.0	-234.8mV	-52.62V	250.6	-234.1mV
54	-48.65V	241.5	-235.3mV	-48.11V	250.5	-239.0mV
55	-50.09V	240.8	-241.3mV	-51.74V	245.8	-217.4mV
56	-48.87V	255.5	-243.4mV	-50.84V	259.4	-222.6mV
57	-50.01V	253.5	-229.7mV	-53.50V	238.6	-215.8mV
58	-49.77V	234.0	-228.9mV	-47.57V	257.7	-222.7mV

SeCoS Corporation

Temperature Cycle Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2015.08.17 ~ 2015.10.08
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
59	-51.06V	253.6	-238.1mV	-48.95V	247.1	-232.5mV
60	-47.68V	255.5	-245.0mV	-50.62V	238.6	-221.3mV
61	-51.08V	260.0	-218.5mV	-50.78V	245.7	-240.7mV
62	-49.03V	241.2	-227.7mV	-50.11V	259.2	-214.0mV
63	-51.65V	251.3	-238.1mV	-48.28V	256.0	-239.1mV
64	-48.18V	246.9	-246.7mV	-51.67V	253.6	-223.9mV
65	-51.49V	240.0	-231.3mV	-49.97V	240.4	-216.2mV
66	-50.26V	248.5	-218.2mV	-48.54V	251.9	-247.4mV
67	-48.45V	234.2	-220.0mV	-49.27V	257.6	-234.4mV
68	-52.72V	242.9	-229.1mV	-48.83V	238.9	-228.7mV
69	-51.46V	253.8	-231.6mV	-51.50V	259.8	-231.9mV
70	-51.24V	259.3	-247.6mV	-50.51V	243.0	-246.0mV
71	-53.41V	253.8	-228.3mV	-50.66V	252.8	-248.1mV
72	-52.98V	239.0	-220.8mV	-52.10V	237.4	-222.3mV
73	-48.34V	255.4	-244.0mV	-52.80V	243.9	-223.5mV
74	-48.67V	247.7	-228.5mV	-52.16V	254.8	-231.0mV
75	-48.57V	245.9	-247.2mV	-47.41V	251.5	-230.3mV
76	-48.10V	239.3	-223.2mV	-50.21V	246.6	-225.9mV
77	-48.94V	233.2	-233.1mV	-51.06V	253.4	-237.6mV

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2015.08.25 ~ 2015.10.06
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
1	-47.50V	243.2	-225.0mV	-48.65V	242.5	-222.0mV
2	-53.00V	259.6	-222.1mV	-52.95V	253.5	-247.3mV
3	-50.90V	238.4	-247.2mV	-53.21V	235.1	-233.5mV
4	-52.12V	243.6	-246.6mV	-51.39V	243.3	-217.4mV
5	-48.38V	252.9	-223.3mV	-52.67V	246.6	-222.7mV
6	-48.15V	250.6	-218.8mV	-49.02V	260.8	-221.4mV
7	-47.44V	258.5	-230.8mV	-48.55V	237.8	-247.4mV
8	-52.60V	244.1	-247.1mV	-47.94V	258.0	-242.8mV
9	-47.75V	258.9	-226.4mV	-53.27V	252.8	-246.1mV
10	-53.74V	234.7	-227.6mV	-53.59V	250.8	-225.1mV
11	-48.94V	242.0	-223.2mV	-52.49V	257.2	-226.5mV
12	-51.44V	236.1	-240.9mV	-51.46V	247.1	-223.8mV
13	-47.62V	245.2	-233.9mV	-50.21V	249.6	-226.2mV
14	-47.50V	236.4	-224.6mV	-47.97V	253.2	-224.0mV
15	-49.89V	255.1	-213.6mV	-52.26V	258.5	-240.3mV
16	-50.00V	242.8	-216.3mV	-51.54V	246.6	-246.2mV
17	-52.07V	245.3	-242.5mV	-48.78V	260.1	-222.8mV
18	-51.67V	257.2	-228.2mV	-53.08V	248.9	-232.5mV
19	-52.09V	256.8	-219.8mV	-50.12V	238.0	-247.5mV
20	-49.99V	251.0	-233.2mV	-51.78V	235.8	-244.4mV
21	-47.31V	244.4	-221.2mV	-51.44V	255.0	-246.7mV
22	-52.55V	243.4	-234.1mV	-47.65V	260.8	-240.1mV
23	-51.93V	260.3	-242.4mV	-49.35V	241.0	-220.3mV
24	-50.47V	260.6	-240.9mV	-47.37V	238.8	-215.9mV
25	-49.17V	239.2	-242.6mV	-53.28V	253.8	-230.0mV
26	-52.32V	252.2	-221.0mV	-49.73V	247.0	-231.3mV
27	-51.49V	248.7	-220.1mV	-48.05V	240.0	-239.0mV
28	-49.74V	257.5	-225.6mV	-51.63V	243.2	-243.6mV
29	-53.47V	243.5	-236.9mV	-51.05V	238.1	-233.3mV

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2015.08.25 ~ 2015.10.06
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
30	-51.50V	241.3	-244.3mV	-53.14V	258.8	-235.7mV
31	-53.43V	235.2	-231.1mV	-51.02V	238.4	-216.6mV
32	-49.08V	254.9	-245.3mV	-53.70V	255.2	-248.0mV
33	-52.78V	235.1	-218.1mV	-48.60V	242.4	-240.1mV
34	-52.75V	241.9	-237.8mV	-51.56V	257.4	-240.5mV
35	-47.52V	259.5	-219.8mV	-49.73V	236.4	-221.9mV
36	-52.70V	246.4	-242.9mV	-52.90V	244.8	-216.0mV
37	-52.05V	244.5	-222.9mV	-52.08V	238.2	-226.4mV
38	-48.74V	256.3	-247.2mV	-51.80V	254.7	-217.8mV
39	-52.08V	245.7	-230.1mV	-50.05V	245.9	-235.3mV
40	-52.07V	240.7	-246.7mV	-51.80V	253.8	-238.7mV
41	-52.06V	244.4	-238.8mV	-51.28V	248.9	-228.5mV
42	-50.14V	241.9	-245.5mV	-47.85V	248.1	-247.6mV
43	-47.90V	255.8	-222.9mV	-50.10V	244.6	-221.8mV
44	-49.84V	234.9	-247.1mV	-51.28V	251.3	-226.1mV
45	-53.03V	260.3	-241.9mV	-50.51V	257.0	-246.8mV
46	-50.89V	249.2	-217.5mV	-48.04V	256.2	-240.3mV
47	-49.92V	252.1	-231.0mV	-48.10V	239.1	-229.5mV
48	-48.43V	257.7	-241.2mV	-50.17V	240.0	-240.7mV
49	-52.37V	233.6	-246.6mV	-47.43V	240.1	-246.8mV
50	-51.98V	238.2	-231.4mV	-53.73V	255.2	-241.2mV
51	-48.93V	258.2	-247.2mV	-50.69V	233.8	-240.0mV
52	-53.42V	245.0	-221.0mV	-53.21V	238.2	-229.8mV
53	-50.88V	253.9	-248.1mV	-50.75V	244.2	-219.2mV
54	-51.25V	246.9	-221.4mV	-51.60V	240.8	-245.4mV
55	-53.41V	247.1	-221.7mV	-49.22V	255.1	-218.2mV
56	-50.66V	248.2	-220.1mV	-53.04V	252.4	-220.3mV
57	-52.12V	255.8	-217.1mV	-48.05V	259.1	-225.9mV
58	-48.94V	241.7	-246.4mV	-50.56V	246.7	-217.8mV

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2015.08.25 ~ 2015.10.06
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
59	-49.57V	242.5	-240.9mV	-51.86V	242.4	-237.1mV
60	-49.02V	243.6	-241.4mV	-47.97V	260.7	-216.6mV
61	-47.50V	233.2	-238.2mV	-47.65V	240.6	-216.8mV
62	-52.86V	252.6	-241.3mV	-51.66V	242.9	-232.3mV
63	-47.43V	245.2	-225.9mV	-52.80V	252.0	-237.4mV
64	-51.30V	259.2	-235.6mV	-52.42V	242.5	-242.8mV
65	-53.06V	258.4	-229.1mV	-50.57V	240.7	-241.8mV
66	-52.22V	254.9	-219.7mV	-52.69V	243.7	-234.4mV
67	-51.25V	236.4	-230.1mV	-49.19V	244.6	-221.9mV
68	-48.97V	239.1	-233.1mV	-50.22V	249.8	-231.3mV
69	-51.62V	253.4	-216.0mV	-50.85V	253.1	-245.7mV
70	-47.91V	254.7	-235.7mV	-49.77V	253.6	-239.1mV
71	-50.77V	239.3	-228.2mV	-53.33V	239.0	-247.1mV
72	-52.60V	240.8	-236.9mV	-48.02V	236.9	-238.3mV
73	-53.21V	248.8	-237.5mV	-51.98V	259.4	-236.9mV
74	-50.55V	252.8	-241.3mV	-48.21V	236.2	-219.1mV
75	-47.41V	259.0	-244.0mV	-49.47V	257.1	-214.7mV
76	-49.08V	253.0	-215.6mV	-49.76V	248.1	-236.3mV
77	-50.78V	241.7	-213.4mV	-49.02V	256.9	-233.5mV

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2015.08.25 ~ 2015.10.06
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
1	-52.02V	237.4	-234.6mV	-49.34V	245.4	-238.8mV
2	-52.44V	245.4	-247.6mV	-47.42V	241.9	-218.2mV
3	-50.85V	250.9	-237.6mV	-53.31V	239.6	-229.5mV
4	-47.56V	240.8	-240.3mV	-47.66V	234.7	-236.9mV
5	-51.14V	234.5	-247.9mV	-51.21V	258.5	-222.1mV
6	-48.92V	242.1	-228.4mV	-51.92V	253.8	-240.4mV
7	-50.79V	247.2	-216.4mV	-48.61V	252.6	-226.6mV
8	-52.24V	234.5	-234.8mV	-49.87V	258.1	-213.4mV
9	-50.71V	255.4	-238.8mV	-48.80V	248.6	-244.6mV
10	-51.94V	245.9	-228.9mV	-51.43V	252.2	-242.4mV
11	-49.67V	236.1	-230.5mV	-52.30V	257.1	-230.2mV
12	-50.11V	259.0	-221.2mV	-52.10V	234.9	-227.3mV
13	-53.74V	256.8	-229.4mV	-49.53V	254.9	-214.8mV
14	-50.94V	237.9	-224.7mV	-53.58V	242.9	-225.6mV
15	-48.53V	259.9	-220.1mV	-53.14V	256.5	-239.7mV
16	-51.76V	251.6	-236.0mV	-49.15V	255.3	-215.4mV
17	-47.58V	235.1	-239.2mV	-47.46V	245.7	-236.3mV
18	-49.02V	256.6	-236.8mV	-50.31V	233.3	-246.0mV
19	-48.71V	257.5	-239.3mV	-52.80V	254.2	-244.0mV
20	-52.71V	258.1	-227.5mV	-49.99V	234.6	-213.6mV
21	-48.28V	249.6	-245.9mV	-52.69V	248.6	-224.6mV
22	-51.48V	236.5	-225.3mV	-47.72V	255.4	-227.5mV
23	-48.97V	235.4	-240.4mV	-52.92V	245.7	-215.9mV
24	-50.19V	247.2	-239.6mV	-51.13V	259.1	-231.8mV
25	-53.69V	237.2	-236.3mV	-50.27V	239.3	-243.0mV
26	-52.21V	251.1	-224.9mV	-49.71V	237.5	-217.5mV
27	-53.49V	237.9	-215.0mV	-52.45V	253.0	-221.1mV
28	-51.91V	256.8	-224.8mV	-48.66V	240.2	-219.2mV
29	-53.05V	245.1	-226.8mV	-52.40V	248.5	-217.2mV

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2015.08.25 ~ 2015.10.06
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
30	-51.00V	248.8	-212.9mV	-47.58V	250.9	-239.6mV
31	-48.43V	238.2	-230.1mV	-48.41V	251.0	-218.7mV
32	-47.41V	235.6	-240.6mV	-51.98V	237.4	-217.0mV
33	-53.89V	243.2	-239.9mV	-47.70V	236.6	-239.6mV
34	-53.18V	246.6	-220.8mV	-50.65V	246.0	-237.4mV
35	-52.14V	243.0	-217.7mV	-51.14V	234.7	-239.1mV
36	-53.67V	233.5	-222.8mV	-50.52V	255.1	-216.7mV
37	-53.53V	236.4	-228.6mV	-50.29V	233.7	-244.5mV
38	-53.51V	257.0	-225.3mV	-52.58V	257.8	-216.5mV
39	-50.47V	233.8	-214.4mV	-51.63V	243.6	-239.5mV
40	-48.06V	253.8	-242.3mV	-48.82V	243.2	-226.8mV
41	-48.25V	251.9	-231.8mV	-50.31V	238.1	-237.4mV
42	-52.49V	253.6	-243.2mV	-51.82V	254.3	-233.1mV
43	-51.13V	255.4	-227.2mV	-50.68V	256.7	-228.5mV
44	-52.00V	246.3	-228.6mV	-50.64V	256.8	-235.4mV
45	-47.83V	254.2	-244.5mV	-49.24V	235.2	-241.2mV
46	-48.13V	253.8	-233.2mV	-49.93V	259.3	-219.3mV
47	-49.03V	259.6	-245.1mV	-52.53V	235.9	-247.7mV
48	-51.70V	260.4	-240.5mV	-48.58V	256.1	-217.6mV
49	-52.08V	258.0	-232.2mV	-53.66V	250.6	-217.0mV
50	-47.35V	256.8	-236.1mV	-52.31V	245.7	-236.3mV
51	-47.64V	233.3	-241.2mV	-50.18V	259.1	-245.2mV
52	-49.48V	259.8	-215.5mV	-51.29V	252.3	-227.4mV
53	-52.70V	234.8	-235.0mV	-52.76V	255.1	-230.2mV
54	-52.22V	241.8	-227.9mV	-47.48V	246.1	-234.3mV
55	-52.70V	251.0	-229.4mV	-53.15V	253.0	-218.2mV
56	-53.85V	253.2	-236.2mV	-49.53V	258.3	-222.7mV
57	-47.35V	252.4	-226.7mV	-52.53V	256.2	-230.8mV
58	-52.16V	243.8	-223.4mV	-47.71V	245.4	-231.1mV

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2015.08.25 ~ 2015.10.06
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
59	-50.15V	254.2	-239.1mV	-48.72V	244.0	-225.3mV
60	-53.15V	249.0	-215.4mV	-50.79V	242.3	-240.4mV
61	-51.25V	245.6	-232.8mV	-49.62V	253.5	-222.5mV
62	-50.86V	238.6	-238.9mV	-51.60V	237.5	-232.7mV
63	-48.97V	252.7	-216.9mV	-48.98V	252.3	-229.6mV
64	-52.58V	252.8	-218.7mV	-50.52V	260.3	-214.2mV
65	-51.77V	256.9	-220.3mV	-53.21V	242.0	-228.6mV
66	-52.72V	259.5	-222.0mV	-51.15V	234.1	-218.8mV
67	-51.79V	241.9	-245.8mV	-49.17V	252.4	-243.6mV
68	-51.18V	239.2	-241.0mV	-48.81V	234.7	-240.4mV
69	-48.07V	234.1	-215.9mV	-50.87V	253.4	-246.7mV
70	-51.63V	244.5	-222.3mV	-49.07V	247.1	-225.5mV
71	-47.89V	240.8	-220.4mV	-52.33V	233.9	-246.7mV
72	-48.08V	234.8	-237.0mV	-53.83V	245.3	-220.0mV
73	-47.41V	239.8	-226.8mV	-47.67V	234.8	-220.1mV
74	-53.09V	247.6	-224.5mV	-50.25V	249.1	-247.5mV
75	-48.69V	245.2	-229.3mV	-52.68V	254.2	-216.5mV
76	-49.21V	245.4	-238.0mV	-49.87V	255.8	-236.5mV
77	-53.66V	242.1	-220.1mV	-51.65V	238.6	-229.8mV

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Solderability Test Data

Report No : T151008-105
Part No : BCP772
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)CEO > -30V@IC=-1mA, IB=0 ； 100 < hFE < 500@VCE=-2V, IC=-1A
VCE(sat) < -500mV@IC=-2A, IB=-200mA
Test Condition: 245℃ ± 5℃, 5Sec
Test Date: 2015.10.08
Test Standard : JESD22 STANDER Method-B102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)	$V_{(BR)CEO}$ (V)	h_{FE}	$V_{CE(sat)}$ (mV)
1	-50.50V	254.6	-236.2mV	-52.33V	242.2	-238.0mV
2	-48.35V	251.1	-242.3mV	-47.56V	251.5	-239.8mV
3	-47.51V	255.0	-224.5mV	-49.83V	236.9	-233.9mV
4	-52.87V	248.2	-237.6mV	-50.36V	260.2	-242.2mV
5	-50.72V	237.7	-233.7mV	-47.41V	260.2	-226.6mV
6	-48.98V	239.2	-223.0mV	-47.43V	251.2	-228.1mV
7	-52.56V	244.9	-228.5mV	-50.61V	260.7	-217.7mV
8	-48.18V	255.0	-247.4mV	-50.97V	255.4	-230.3mV
9	-53.88V	235.4	-248.2mV	-50.16V	258.4	-239.7mV
10	-50.64V	260.7	-224.7mV	-51.12V	237.7	-213.2mV

Made By: King Huang

Approval: Peter Yang